PCN	Number:	20190	20190506000.1						Ρ	CN I	Date:	May 15, 2019
Title:		Add C	u as Alterna	ati	ve	Wire Ba	ase Meta	al for Sel	lected Device(s)			
Prop	osed 1 st Ship	Aug 1	5, 2019				Es	Estimated Sample Date provided at				
Chan	ge Type:							anabin	<u></u>			sample request
	Assembly Site			[[Desig	ŋn			Wafer Bump Site		
	Assembly Proce	SS		Ī		Data	Sheet				Wafe	er Bump Material
	Assembly Mater	ials				Part r	number	change			Wafe	er Bump Process
	Mechanical Spec	cificatio	n	[Test S	Site				Wafe	er Fab Site
	Packing/Shippin	g/Labe	ling			Test	Process				Wafe	er Fab Materials
											Wafe	er Fab Process
						PCN D	Details	5				
Desc	ription of Char	nge:										
Texas an ad remai Grou	Instruments is ditional bond wi in in current ass <u>p 1 Devices:</u>	pleased re optic embly f	d to annour on for devic facility and	nce es pi	e th isi ece	ne quali ted in " part cl	ification Product hanges	of new a affectec as follow	asse 1″ s 's:	emb ectio	ly ma on bel	terial set to add Cu as low. Devices will
	Materia		Curren	t		Prop	posed					
	Wire		Au			(Cu					
Not	e: Devices highl	ighted	in <mark>Yellow</mark> wi	ill	cor	ntinue t	to use A	u wire fo	r D	ie to	o Die	bonding
Grou	p 2 Devices:											
	Materia		Curren	t		Prop	posed					
	Protective Ove	ercoat	BCB				PI					
	Wire		Au			Cu						
Reas	on for Change	•										
 Continuity of supply. 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties 2) Maximize flexibility within our Assembly/Test production sites. 3) Cu is easier to obtain and stock 												
Antic	ipated impact	on Fit,	Form, Fu	nc	tio	n, Qua	ality or	Reliabil	ity	(po	sitive	e / negative):
None												
Anticipated impact on Material Declaration												
No Impact to the Material Declaration				M d fr T n r	Aaterial Iriven fr ollowing elease t <u>I Eco-Ir</u> naterial equirem	Declarat om prod the prod he revise <u>nfo webs</u> meeting <u>nents wit</u>	ion: duct duc ed r ite. cu h tł	s or ion o tion repo The rren his P	Produ data a relea rts ca ere is t regu PCN ch	act Content reports are and will be available se. Upon production n be obtained from the no impact to the alatory compliance mange.		
Chan	ges to product	t <mark>ident</mark> i	ification re	esi	ulti	ing fro	m this	PCN:				
None												
Group 1 Product Affected:												

ADC16V130CISQ/NOPB	LM5101ASDX-1/NOPB	LMK01020ISQ/NOPB	LMK04031BISQX/S7002381
ADC16V130CISQE/NOPB	LM5102SD/NOPB	LMK01020ISQE/NOPB	LMK04033BISQ/NOPB
ADC16V130CISQX/NOPB	LM5102SDX/NOPB	LMK01020ISQX/NOPB	LMK04033BISQE/NOPB
ADC31JB68RTAT	LM5104SD/NOPB	LMK02000ISQ/NOPB	LMK04033BISQE/S7002427
DS110DF111SQ/NOPB	LM5104SDX/NOPB	LMK02002ISQ/NOPB	LMK04033BISQX/NOPB
DS110DF111SQE/NOPB	LM5105SD/NOPB	LMK02002ISQX/NOPB	LMK04100SQ/NOPB
DS125DF111SQ	LM5105SDX/NOPB	LMK03000CISQ/NOPB	LMK04100SQE/NOPB
DS125DF111SQE	LM5107SD/NOPB	LMK03000CISQX/NOPB	LMK04100SQX/NOPB
LDC6996AIME/NOPB	LM5109ASDX/NOPB	LMK03000DISQ/NOPB	LMK04101SQ/NOPB
LDC6996AIMX/NOPB	LM5109BSDX/NOPB	LMK03000DISQE/NOPB	LMK04101SQE/NOPB
LM10000SD/NOPB	LM5115SD/NOPB	LMK03000DISQX/NOPB	LMK04101SQX/NOPB
LM10000SDE/NOPB	LM5115SDX/NOPB	LMK03000ISQ/NOPB	LMK04102SQ/NOPB
LM10000SDX/NOPB	LM5161PWPR	LMK03001CISQ/NOPB	LMK04102SQE/NOPB
LM10515SQ/NOPB	LM5161PWPT	LMK03001CISQX/NOPB	LMK04102SQX/NOPB
LM10515SQ-A/NOPB	LMC6024IM/NOPB	LMK03001DISQ/NOPB	LMK04110SQ/NOPB
LM10515SQE/NOPB	LMC6024IMX/NOPB	LMK03001DISQE/NOPB	LMK04110SQE/NOPB
LM10515SQE-A/NOPB	LMC6034IM	LMK03001DISQX/NOPB	LMK04110SQX/NOPB
LM10515SQE-B/NOPB	LMC6034IM/NOPB	LMK03001ISQ/NOPB	LMK04111SQ/NOPB
LM10515SQX/NOPB	LMC6034IMX/NOPB	LMK03002CISQ/NOPB	LMK04111SQE/NOPB
LM10515SQX-A/NOPB	LMC6036IM/NOPB	LMK03002CISQ/S7002367	LMK04111SQX/NOPB
LM10515SQX-B/NOPB	LMC6036IMX/NOPB	LMK03002CISQX/NOPB	LMK04131SQ/NOPB
LM25085ASDX/NOPB	LMC6044AIM	LMK03002ISQ/NOPB	LMK04131SQE/NOPB
LM25101ASD-1/NOPB	LMC6044AIM/NOPB	LMK03002ISQX/NOPB	LMK04131SQX/NOPB
LM25101ASDX/NOPB	LMC6044AIMX/NOPB	LMK03033CISQ/NOPB	LMK04133SQ/NOPB
LM25101CSD/NOPB	LMC6044IM/NOPB	LMK03033CISQE/NOPB	LMK04133SQE/NOPB
LM25115SDX/NOPB	LMC6044IMX/NOPB	LMK03033CISQX/NOPB	LMK04133SQX/NOPB
LM2647LQ/NOPB	LMC6484AIMX	LMK03033ISQ/NOPB	LP3972SQ-0514/NOPB
LM5001SDX/NOPB	LMC6484AIMX/SL163019	LMK03033ISQE/NOPB	LP3972SQ-5810/NOPB
LM5002SDX/NOPB	LMC660AIM	LMK03033ISQX/NOPB	LP3972SQ-A413/NOPB
LM5025ASD/NOPB	LMC660AIM/NOPB	LMK03200ISQ/NOPB	LP3972SQ-A514/NOPB
LM5025ASDX/NOPB	LMC660AIMX	LMK03200ISQE/NOPB	LP3972SQ-E514/NOPB
LM5025BSD/NOPB	LMC660AIMX/NOPB	LMK03200ISQX/NOPB	LP3972SQ-I414/NOPB
LM5025SD/NOPB	LMC660CM	LMK04000BISQ/NOPB	LP3972SQ-I514/NOPB
LM5027SQ-1/NOPB	LMC660CM/ELLI518	LMK04000BISQE/NOPB	LPC660AIM/NOPB
LM5035BSQX/NOPB	LMC660CM/NOPB	LMK04000BISQX/NOPB	LPC660AIMX/NOPB
LM5035CSQ/NOPB	LMC660CMX/NOPB	LMK04001BISQ/NOPB	LPC660IM/NOPB
LM5035CSQX/NOPB	LMH0318RTWR	LMK04001BISQE/NOPB	LPC660IMX/NOPB
LM5039SQ/NOPB	LMH0318RTWT	LMK04001BISQX/NOPB	SM74104SDE/NOPB
LM5039SQX/NOPB	LMH0346SQ/NOPB	LMK04001BISQX/S7002440	SM74104SDX/NOPB
LM5041ASD/NOPB	LMH0346SQE/NOPB	LMK04002BISQ/NOPB	UCC20520DW
LM5041SD	LMH0356SQ-40/NOPB	LMK04002BISQE/NOPB	UCC20520DWR
LM5041SD/NOPB	LMH0356SQE-40/NOPB	LMK04002BISQX/NOPB	UCC21520ADW
LM5041SDX/NOPB	LMH1218RTWR	LMK04010BISQ/NOPB	UCC21520ADWR

LM5085SDX/NOPB	LMH1218RTWT	LMK04010BISQE/NOPB	UCC21520DW		
LM5100ASD/NOPB	LMK01000ISQ/NOPB	LMK04010BISQX/NOPB	UCC21520DWR		
LM5100BSD/NOPB	LMK01000ISQE/NOPB	LMK04011BISQ/NOPB	UCC21521ADW		
LM5101ASD	LMK01000ISQE/S7002207	LMK04011BISQE/NOPB	UCC21521ADWR		
LM5101ASD/NOPB	LMK01000ISQX/NOPB	LMK04011BISQX/NOPB	UCC21521CDW		
LM5101ASD-1/NOPB	LMK01010ISQ/NOPB	LMK04031BISQ/NOPB	UCC21521CDWR		
LM5101ASDX	LMK01010ISQE/NOPB	LMK04031BISQE/NOPB	UCC21521DW		
LM5101ASDX/NOPB	LMK01010ISQX/NOPB	LMK04031BISQX/NOPB	UCC21521DWR		
Group 2 Product Affected:					
LMP92066PWP	LMP92066PWPR				

Group 1 Qualification Report

Qualification Report

Approved on 11-Nov-2013

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: DS90CP22MXA1CL	Qual Device: LMV324MX	Qual Device: LP2995MXNOPB	Qual Device: LMC6482AIM/NOPB
PC	PreCon Level 1	Level 1-260C	3/462/0	-	3/462/0	3/693/0
HAST	Biased HAST, 130C/85%RH	96/hrs. @130C	-	-	-	3/231/0
AC	Autoclave 121C	96HRS	3/231/0	-	3/231/0	3/231/0
тс	Temperature Cycle, -65/150C	TMCL500X	3/231/0	-	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	1000 hrs. @150C	-	-	-	1/77/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	-	Pass	Pass	Pass
DPA	Destructive Physical Analysis Post 500 Temp Cycle	x-section and de process to examine assembly robustness, Check for stich bond and bond pad integrity	3/15/0	-	3/15/0	3/15/0
YLD	FTY and Bin Summary	Compare against baseline	-	Pass	Pass	Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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Qualification Report Approved on 23-Sep-2014

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Тур е	Test Name / Condition	Duratio n	Qual Device: DP83848T SQ	Qual Device: DS91M040TSQ AW	Qual Device: DS100DX410E L16	Qual Device: DS80PCI402A 2TT	Qual Device: LMH0366SQEN OPB	Qual Device: LMH0394SQ/N OPB
PC	PreCon Level 1	Level 1- 260C					3/720/0	
РС	PreCon Level 2	Level 2- 260C	3/1079/0		-	3/720/0	-	-
PC	PreCon Level 3	Level 3- 260C	-	1/255/0	3/720/0	-	-	3/231/0
HAST	Biased HAST, 130C/85%RH	96/hrs. @130C	-	-	-	-	-	3/231/0
AC	Autoclave 121C	96HRS	3/231/0	1/77/0	3/231/0	3/231/0	3/231/0	-
UHAS T	Unbiased HAST 130C/85%RH	unHAST- 96 HRS/-	3/231/0	1/77/0	3/231/0	3/231/0	3/231/0	-
тс	Temperature Cycle, - 65/150C	TMCL500 X	3/231/0	1/77/0	3/231/0	3/231/0	3/231/0	-
HTSL	High Temp Storage Bake 170C	420 hrs. @170C	3/231/0	-	-	3/231/0	-	-
ED	Side By Side Electrical Characterizati on.	Per Datasheet Parameter s	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	-
MQ	Manufacturab ility (Assembly)	(per mfg. Site specificati on)	Pass	Pass	Pass	Pass	Pass	Pass
MSL	Thermal Path Integrity	Level 2- 260C	3/30/0	1/22/0	3/66/0	3/66/0	3/66/0	-
DPA	Destructive Physical Analysis Post 500 Temp Cycle	x-section and de process to examine assembly robustnes s, Check for stich bond and bond pad integrity	3/3/0	-	3/15/0	3/15/0	3/15/0	1/5/0 Post 96 hours HAST
YLD	FTY and Bin Summary	Compare against baseline	Pass	Pass	Pass	Pass	Pass	Pass

- QBS: Qual By Similarity

- Qual Device DS100DX410EL16 is qualified at LEVEL3-260C

- Qual Device DS80PCI402A2TT is gualified at LEVEL2-260C

- Qual Device LMH0366SQENOPB is gualified at LEVEL1-260C

- Qual Device LMH0394SQ/NOPB is gualified at -
- Qual Device LMH0394SQ/NOPB REV A is gualified at LEVEL3-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours - The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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Qualification Report Approved on 27-Dec-2018

Oualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: UCC21520QDWR
AC	Autoclave 121C	96 Hours	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	3/77/0
HTOL	Life Test, 125C	1000 Hours	1/77/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0

- Qual Device UCC21520QDWR is gualified at LEVEL2-260C

- Device UCC21520QDWR contains multiple dies.

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours,

150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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Qualification Report Approved on 25-Apr-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Turne	Test Nome / Condition	Duration	Qual Device:	Qual Device:
туре	Test Name / Condition	Duration	LMX2581ESQJTYY	<u>LP3971SQ2GZ85K</u>

Туре	Test Name / Condition	Duration	Qual Device: <u>LMX2581ESQJTYY</u>	Qual Device: <u>LP3971SQ2GZ85K</u>
HAST	Biased HAST, 110C/85%RH	264 Hours	3/231/0	3/231/0
HAST	Biased HAST, 110C/85%RH	528 Hours (for info only)	3/231/0	3/231/0
TC	Temperature Cycle, - 65/150C	500 Cycles	-	3/231/0
UHAST	Unbiased HAST 110C/85%RH	264 Hours	-	3/231/0
WBP	Bond Pull	Wires	3/228/0	3/228/0
WBS	Ball Bond Shear	Wires	3/228/0	3/228/0

- Qual Device LMX2581ESQJTYY is qualified at LEVEL3-260CG

- Qual Device LP3971SQ2GZ85K is qualified at LEVEL1-260CG

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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Group 2 Qualification Report

Approved on 26-Mar-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>LMP92066PWPR</u>
AC	Autoclave 121C	96 Hours	3/231/0
HTOL	Life Test, 125C	1000 Hours	3/231/0
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0
тс	Temperature Cycle, -65/150C	500 Cycles	3/231/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass

- QBS: Qual By Similarity

- Qual Device LMP92066PWPR is qualified at LEVEL1-260CG

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/ Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

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